

Features

- 5 ns pin-to-pin logic delays
- System frequency up to 178 MHz
- 72 macrocells with 1,600 usable gates
- Available in small footprint packages
 - 44-pin PLCC (34 user I/O pins)
 - 44-pin VQFP (34 user I/O pins)
 - 48-pin CSP (38 user I/O pins)
 - 64-pin VQFP (52 user I/O pins)
 - 100-pin TQFP (72 user I/O pins)
- Optimized for high-performance 3.3V systems
 - Low power operation
 - 5V tolerant I/O pins accept 5V, 3.3V, and 2.5V signals
 - 3.3V or 2.5V output capability
 - Advanced 0.35 micron feature size CMOS Fast FLASH™ technology
- Advanced system features
 - In-system programmable
 - Superior pin-locking and routability with Fast CONNECT™ II switch matrix
 - Extra wide 54-input Function Blocks
 - Up to 90 product-terms per macrocell with individual product-term allocation
 - Local clock inversion with three global and one product-term clocks
 - Individual output enable per output pin
 - Input hysteresis on all user and boundary-scan pin inputs
 - Bus-hold circuitry on all user pin inputs
 - Full IEEE Standard 1149.1 boundary-scan (JTAG)
- Fast concurrent programming
- Slew rate control on individual outputs
- Enhanced data security features
- Excellent quality and reliability
 - Endurance exceeding 10,000 program/erase cycles
 - 20 year data retention
 - ESD protection exceeding 2,000V
- Pin-compatible with 5V-core XC9572 device in the 44-pin PLCC package and the 100-pin TQFP package

Description

The XC9572XL is a 3.3V CPLD targeted for high-performance, low-voltage applications in leading-edge communications and computing systems. It is comprised of four 54V18 Function Blocks, providing 1,600 usable gates with propagation delays of 5 ns. See Figure 2 for architecture overview.

Power Estimation

Power dissipation in CPLDs can vary substantially depending on the system frequency, design application and output loading. To help reduce power dissipation, each macrocell in a XC9500XL device may be configured for low-power mode (from the default high-performance mode). In addition, unused product-terms and macrocells are automatically deactivated by the software to further conserve power.

For a general estimate of I_{CC} , the following equation may be used:

$$I_{CC}(mA) = MC_{HS}(0.175 * PT_{HS} + 0.345) + MC_{LP}(0.052 * PT_{LP} + 0.272) + 0.04 * MC_{TOG}(MC_{HS} + MC_{LP}) * f$$

where:

MC_{HS} = # macrocells in high-speed configuration

PT_{HS} = average number of high-speed product terms per macrocell

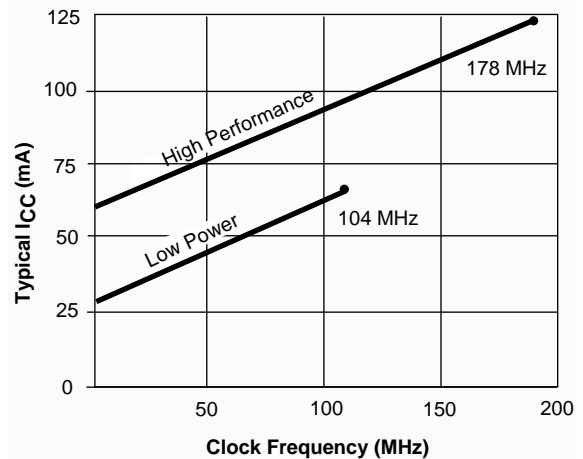
MC_{LP} = # macrocells in low power configuration

PT_{LP} = average number of low power product terms per macrocell

f = maximum clock frequency

$MCTOG$ = average % of flip-flops toggling per clock (~12%)

This calculation was derived from laboratory measurements of an XC9500XL part filled with 16-bit counters and allowing a single output (the LSB) to be enabled. The actual I_{CC} value varies with the design application and should be verified during normal system operation. Figure 1 shows the above estimation in a graphical form. For a more detailed discussion of power consumption in this device, see Xilinx application note [XAPP114, "Understanding XC9500XL CPLD Power."](#)



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Figure 1: Typical I_{CC} vs. Frequency for XC9572XL

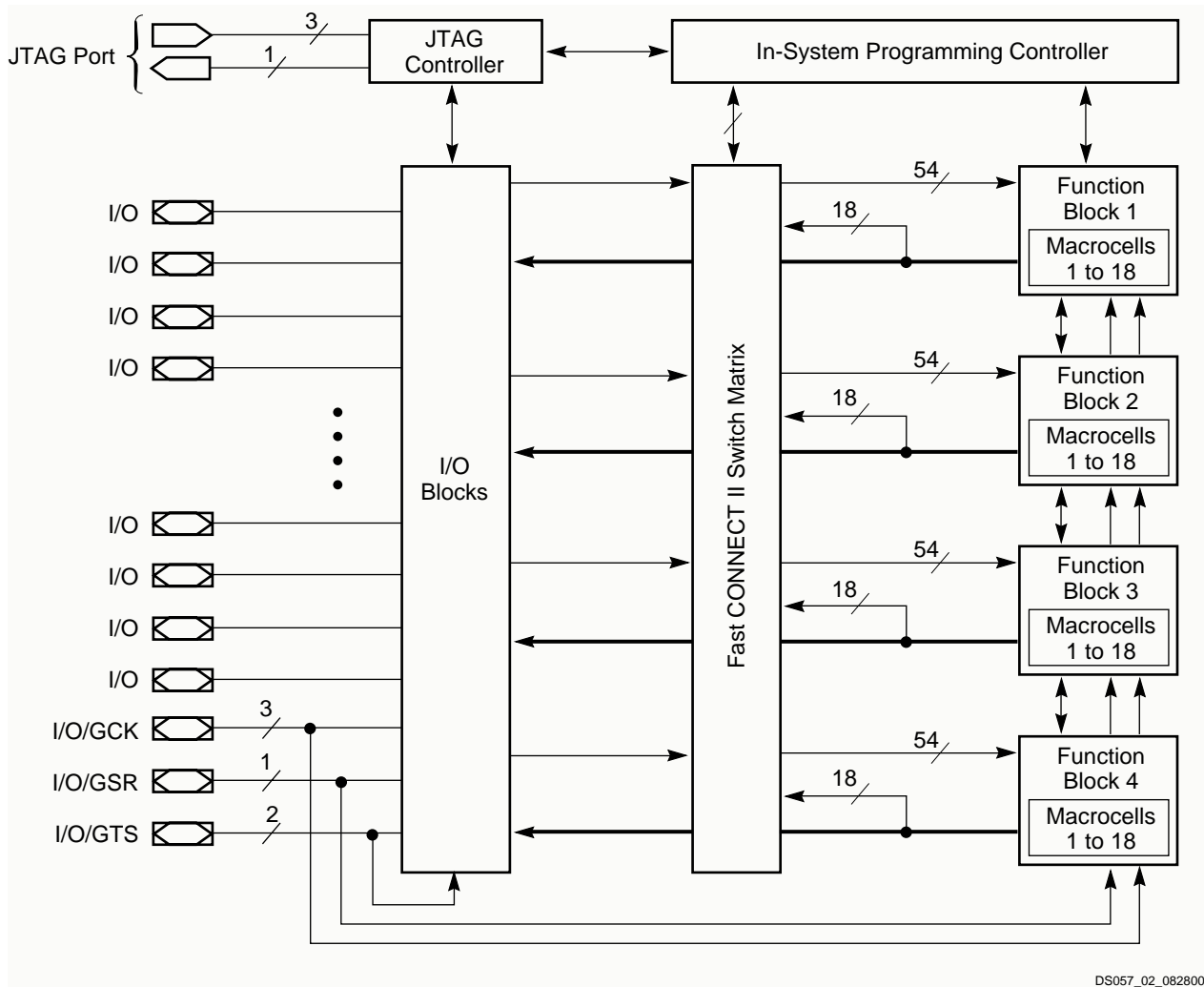


Figure 2: XC9572XL Architecture
 Function Block outputs (indicated by the bold line) drive the I/O Blocks directly.

Absolute Maximum Ratings

Symbol	Description	Value	Units
V_{CC}	Supply voltage relative to GND	-0.5 to 4.0	V
V_{IN}	Input voltage relative to GND ⁽¹⁾	-0.5 to 5.5	V
V_{TS}	Voltage applied to 3-state output ⁽¹⁾	-0.5 to 5.5	V
T_{STG}	Storage temperature (ambient)	-65 to +150	°C
T_{SOL}	Maximum soldering temperature (10s @ 1/16 in. = 1.5 mm)	+260	°C
T_J	Junction temperature	+150	°C

Notes:

- Maximum DC undershoot below GND must be limited to either 0.5V or 10 mA, whichever is easier to achieve. During transitions, the device pins may undershoot to -2.0 V or overshoot to +7.0V, provided this over- or undershoot lasts less than 10 ns and with the forcing current being limited to 200 mA.
- Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.

Recommended Operation Conditions

Symbol	Parameter	Min	Max	Units	
V_{CCINT}	Supply voltage for internal logic and input buffers	Commercial $T_A = 0^{\circ}\text{C}$ to 70°C	3.0	3.6	V
		Industrial $T_A = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$	3.0	3.6	V
V_{CCIO}	Supply voltage for output drivers for 3.3V operation	3.0	3.6	V	
	Supply voltage for output drivers for 2.5V operation	2.3	2.7	V	
V_{IL}	Low-level input voltage	0	0.80	V	
V_{IH}	High-level input voltage	2.0	5.5	V	
V_O	Output voltage	0	V_{CCIO}	V	

Quality and Reliability Characteristics

Symbol	Parameter	Min	Max	Units
T_{DR}	Data Retention	20	-	Years
N_{PE}	Program/Erase Cycles (Endurance)	10,000	-	Cycles
V_{ESD}	Electrostatic Discharge (ESD)	2,000	-	Volts

DC Characteristic Over Recommended Operating Conditions

Symbol	Parameter	Test Conditions	Min	Max	Units
V_{OH}	Output high voltage for 3.3V outputs	$I_{OH} = -4.0\text{ mA}$	2.4	-	V
	Output high voltage for 2.5V outputs	$I_{OH} = -500\text{ }\mu\text{A}$	90% V_{CCIO}	-	V
V_{OL}	Output low voltage for 3.3V outputs	$I_{OL} = 8.0\text{ mA}$	-	0.4	V
	Output low voltage for 2.5V outputs	$I_{OL} = 500\text{ }\mu\text{A}$	-	0.4	V
I_{IL}	Input leakage current	$V_{CC} = \text{Max}; V_{IN} = \text{GND or } V_{CC}$	-	± 10	μA
I_{IH}	I/O high-Z leakage current	$V_{CC} = \text{Max}; V_{IN} = \text{GND or } V_{CC}$	-	± 10	μA
I_{IH}	I/O high-Z leakage current	$V_{CC} = \text{Max}; V_{CCIO} = \text{Max}; V_{IN} = \text{GND or } 3.6\text{V}$	-	± 10	μA
		$V_{CC} \text{ Min} < V_{IN} < 5.5\text{V}$	-	± 50	μA
C_{IN}	I/O capacitance	$V_{IN} = \text{GND}; f = 1.0\text{ MHz}$	-	10	pF
I_{CC}	Operating supply current (low power mode, active)	$V_{IN} = \text{GND}, \text{ No load}; f = 1.0\text{ MHz}$	20 (Typical)		mA

AC Characteristics

Symbol	Parameter	XC9572XL-5		XC9572XL-7		XC9572XL-10		Units
		Min	Max	Min	Max	Min	Max	
T_{PD}	I/O to output valid	-	5.0	-	7.5	-	10.0	ns
T_{SU}	I/O setup time before GCK	3.7	-	4.8	-	6.5	-	ns
T_H	I/O hold time after GCK	0	-	0	-	0	-	ns
T_{CO}	GCK to output valid	-	3.5	-	4.5	-	5.8	ns
f_{SYSTEM}	Multiple FB internal operating frequency	-	178.6	-	125.0	-	100.0	MHz
T_{PSU}	I/O setup time before p-term clock input	1.7	-	1.6	-	2.1	-	ns
T_{PH}	I/O hold time after p-term clock input	2.0	-	3.2	-	4.4	-	ns
T_{PCO}	P-term clock output valid	-	5.5	-	7.7	-	10.2	ns
T_{OE}	GTS to output valid	-	4.0	-	5.0	-	7.0	ns
T_{OD}	GTS to output disable	-	4.0	-	5.0	-	7.0	ns
T_{POE}	Product term OE to output enabled	-	7.0	-	9.5	-	11.0	ns
T_{POD}	Product term OE to output disabled	-	7.0	-	9.5	-	11.0	ns
T_{AO}	GSR to output valid	-	10.0	-	12.0	-	14.5	ns
T_{PAO}	P-term S/R to output valid	-	10.5	-	12.6	-	15.3	ns
T_{WLH}	GCK pulse width (High or Low)	2.8	-	4.0	-	4.5	-	ns
T_{PLH}	P-term clock pulse width (High or Low)	5.0	-	6.5	-	7.0	-	ns

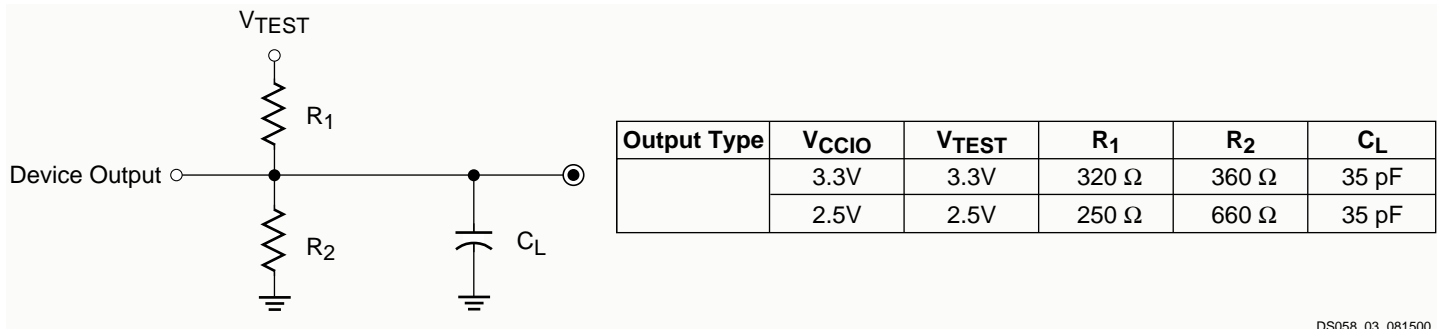


Figure 3: AC Load Circuit

Internal Timing Parameters

Symbol	Parameter	XC9572XL-5		XC9572XL-7		XC9572XL-10		Units
		Min	Max	Min	Max	Min	Max	
Buffer Delays								
T_{IN}	Input buffer delay	-	1.5	-	2.3	-	3.5	ns
T_{GCK}	GCK buffer delay	-	1.1	-	1.5	-	1.8	ns
T_{GSR}	GSR buffer delay	-	2.0	-	3.1	-	4.5	ns
T_{GTS}	GTS buffer delay	-	4.0	-	5.0	-	7.0	ns
T_{OUT}	Output buffer delay	-	2.0	-	2.5	-	3.0	ns
T_{EN}	Output buffer enable/disable delay	-	0	-	0	-	0	ns
Product Term Control Delays								
T_{PTCK}	Product term clock delay	-	1.6	-	2.4	-	2.7	ns
T_{PTSR}	Product term set/reset delay	-	1.0	-	1.4	-	1.8	ns
T_{PTTS}	Product term 3-state delay	-	5.5	-	7.2	-	7.5	ns
Internal Register and Combinatorial Delays								
T_{PDI}	Combinatorial logic propagation delay	-	0.5	-	1.3	-	1.7	ns
T_{SUI}	Register setup time	2.3	-	2.6	-	3.0	-	ns
T_{HI}	Register hold time	1.4	-	2.2	-	3.5	-	ns
T_{ECSU}	Register clock enable setup time	2.4	-	2.6	-	3.0	-	ns
T_{ECHO}	Register clock enable hold time	1.4	-	2.2	-	3.5	-	ns
T_{COI}	Register clock to output valid time	-	0.4	-	0.5	-	1.0	ns
T_{AOI}	Register async. S/R to output delay	-	6.0	-	6.4	-	7.0	ns
T_{RAI}	Register async. S/R recover before clock	5.0		7.5		10.0		ns
T_{LOGI}	Internal logic delay	-	1.0	-	1.4	-	1.8	ns
T_{LOGILP}	Internal low power logic delay	-	5.0	-	6.4	-	7.3	ns
Feedback Delays								
T_F	Fast CONNECT II feedback delay	-	1.9	-	3.5	-	4.2	ns
Time Adders								
T_{PTA}	Incremental product term allocator delay	-	0.7	-	0.8	-	1.0	ns
T_{SLEW}	Slew-rate limited delay	-	3.0	-	4.0	-	4.5	ns

XC9572XL I/O Pins

Function Block	Macro-cell	PC44	VQ44	CS48	VQ64	TQ100	BScan Order
1	1	-	-	-	-	16	213
1	2	1	39	D7	8	13	210
1	3	-	-	D4	12	18	207
1	4	-	-	-	13	20	204
1	5	2	40	D6	9	14	201
1	6	3	41	C7	10	15	198
1	7	-	-	-	-	25	195
1	8	4	42	C6	11	17	192
1	9	5 ⁽¹⁾	43 ⁽¹⁾	B7 ⁽¹⁾	15 ⁽¹⁾	22 ⁽¹⁾	189
1	10	-	-	-	18	28	186
1	11	6 ⁽¹⁾	44 ⁽¹⁾	B6 ⁽¹⁾	16 ⁽¹⁾	23 ⁽¹⁾	183
1	12	-	-	-	23	33	180
1	13	-	-	-	-	36	177
1	14	7 ⁽¹⁾	1 ⁽¹⁾	A7 ⁽¹⁾	17 ⁽¹⁾	27 ⁽¹⁾	174
1	15	8	2	A6	19	29	171
1	16	-	-	-	-	39	168
1	17	9	3	C5	20	30	165
1	18	-	-	-	-	40	162
2	1	-	-	-	-	87	159
2	2	35	29	F4	60	94	156
2	3	-	-	-	58	91	153
2	4	-	-	-	59	93	150
2	5	36	30	G5	61	95	147
2	6	37	31	F5	62	96	144
2	7	-	-	-	-	3 ⁽²⁾	141
2	8	38	32	G6	63	97	138
2	9	39 ⁽¹⁾	33 ⁽¹⁾	G7 ⁽¹⁾	64 ⁽¹⁾	99 ⁽¹⁾	135
2	10	-	-	-	1	1	132
2	11	40 ⁽¹⁾	34 ⁽¹⁾	F6 ⁽¹⁾	2 ⁽¹⁾	4 ⁽¹⁾	129
2	12	-	-	-	4	6	126
2	13	-	-	-	-	8	123
2	14	42 ⁽³⁾	36 ⁽³⁾	E6 ⁽³⁾	5 ⁽³⁾	9 ⁽³⁾	120
2	15	43	37	E7	6	11	117
2	16	-	-	-	-	10	114
2	17	44	38	E5	7	12	111
2	18	-	-	-	-	92	108

Function Block	Macro-cell	PC44	VQ44	CS48	VQ64	TQ100	BScan Order
3	1	-	-	-	-	41	105
3	2	11	5	B5	22	32	102
3	3	-	-	C4	31	49	99
3	4	-	-	-	32	50	96
3	5	12	6	A4	24	35	93
3	6	-	-	-	34	53	90
3	7	-	-	-	-	54	87
3	8	13	7	B4	25	37	84
3	9	14	8	A3	27	42	81
3	10	-	-	D3	39	60	78
3	11	18	12	B2	33	52	75
3	12	-	-	-	40	61	72
3	13	-	-	-	-	63	69
3	14	19	13	B1	35	55	66
3	15	20	14	C2	36	56	63
3	16	24	18	D2	42	64	60
3	17	22	16	C3	38	58	57
3	18	-	-	-	-	59	54
4	1	-	-	-	-	65	51
4	2	25	19	E1	43	67	48
4	3	-	-	-	46	71	45
4	4	-	-	-	47	72	42
4	5	26	20	E2	44	68	39
4	6	-	-	E4	49	76	36
4	7	-	-	-	-	77	33
4	8	27	21	F1	45	70	30
4	9	-	-	-	-	66	27
4	10	-	-	-	51	81	24
4	11	28	22	G1	48	74	21
4	12	-	-	-	52	82	18
4	13	-	-	-	-	85	15
4	14	29	23	F2	50	78	12
4	15	33	27	E3	56	89	9
4	16	-	-	-	-	86	6
4	17	34	28	G4	57	90	3
4	18	-	-	-	-	79	0

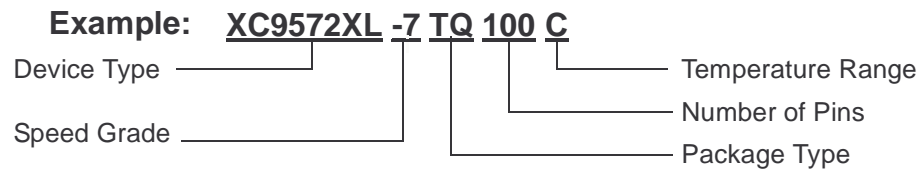
Notes:

1. Global control pin.
2. GTS1 for TQ100.
3. GTS1 for PC44, VQ44, CS48, and VQ64.

XC9572XL Global, JTAG and Power Pins

Pin Type	PC44	VQ44	CS48	VQ64	TQ100
I/O/GCK1	5	43	B7	15	22
I/O/GCK2	6	44	B6	16	23
I/O/GCK3	7	1	A7	17	27
I/O/GTS1	42	36	E6	5	3
I/O/GTS2	40	34	F6	2	4
I/O/GSR	39	33	G7	64	99
TCK	17	11	A1	30	48
TDI	15	9	B3	28	45
TDO	30	24	G2	53	83
TMS	16	10	A2	29	47
V _{CCINT} 3.3V	21, 41	15, 35	C1, F7	3, 37	5, 57, 98
V _{CCIO} 2.5V/3.3V	32	26	G3	26, 55	26, 38, 51, 88
GND	10, 23, 31	4, 17, 25	A5, D1, F3	14, 21, 41, 54	21, 31, 44, 62, 69, 75, 84, 100
No Connects	-	-	-	-	2, 7, 19, 24, 34, 43, 46, 73, 80

Ordering Information



Device Ordering Options

Speed	
-10	10 ns pin-to-pin delay
-7	7.5 ns pin-to-pin delay
-5	5 ns pin-to-pin delay

Package	
PC44	44-pin Plastic Lead Chip Carrier (PLCC)
VQ44	44-pin Quad Flat Pack (VQFP)
CS48	48-pin Chip Scale Package
VQ64	64-pin Quad Flat Pack (VQFP)
TQ100	100-pin Thin Quad Flat Pack (TQFP)

Temperature	
C = Commercial	$T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$
I = Industrial	$T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$

Component Availability

Pins		44	44	48	64	100
Type		Plastic PLCC	Plastic VQFP	Plastic CSP	Plastic VQFP	Plastic TQFP
Code		PC44	VQ44	CS48	VQ64	TQ100
XC9572XL	-10	C, I	C, I	C, I	C, I	C, I
	-7	C, I	C, I	C, I	C, I	C, I
	-5	C	C	C	C	C

Notes:

1. C = Commercial ($T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$); I = Industrial ($T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$).

Revision History

The following table shows the revision history for this document.

Date	Version	Revision
09/28/98	1.0	Initial Xilinx release.
08/28/01	1.1	Added VQ44 package.
06/20/02	1.2	Updated I_{CC} equation, page 1. Updated Component Availability table. Added additional I_{IH} test conditions and measurements to DC Characteristics table.